E lectrostatic interface tuning in correlated superconducting heterostructures

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A n electrostatic eld, which is applied to a gated high-tem perature superconducting (HTSC) lm, is believed to a ect the lm similar to charge doping. A nalyzing the pairing in term s of at{J m odel, we show that a coupling to electric dipoles and phonons at the interface of lm and dielectric gate localizes the injected charge and leads to a superconductor-insulator transition. This results in a dram aticm odi cation of the doping dependent phase diagram close to and above the optim aldoping which is expected to shed light on recent electric eld-e ect experiments with HTSC cuprates.

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I. IN TRODUCTION

Interface physics of strongly correlated oxides is a rapidly developing branch of materials science. In heterostructures of ultrathin correlated oxide Ims, charge and spin states are reconstructed at the interfaces and hence a ect the electronic properties of the entire system^{1,2}. This interface-controlled behavior provides new opportunities for oxide- Im electronics, where a powerful tool for tuning the heterostructure properties is the electric eld^{1,3}. In high-tem perature superconducting oxides, electric elds can be used to switch between superconducting and insulating states by electrostatically tuning the free carrier density^{4,5}. In contrast to chem ical doping, where the modi cations in the doping level are inevitably related to changes in chemical bonding and m icrostructure, the eld-e ect experim ents are expected to only modify charge, keeping the microstructure xed.

In superconducting eld-e ect transistors (SuFET's), an electric eld is applied to a dielectric gate and sweeps charge carriers into a HTSC - Im in the drain-source channel. The gate polarization attracts the injected carriers at the gate/ Im -interface. It thereby creates an accumulation region with a shifted local T_c which, for a nm - thick lm, should result in a tuning of the global T_c.W ith the assumption of a xed interface m icrostructure, the eld-induced T_c shift should be fully determined by the electric eld doping. However, whereas in underdoped HTSC cuprate Ims the observed T_c shift is about 5{18 K, in the overdoped $\text{Im s } T_c$ is not substantially changed by the eld^{4,5}. This striking doping dependence is usually explained in terms of a Thom as-Ferm i screening length TF which suggests a stronger exponential decay of accum ulated charge inside the overdoped Im s with higher total carrier density. However, in anisotropic systems, the quantum mechanically determ ined spread of the charge from the interface is greater and decays slower, in distinction to the classical Thom as-Ferm i approach⁶. As the cuprate Im s contain CuO_2 planes with an interplanar distance 1 nm, only a particular amount of injected charge is accumulated in the

rst plane at the interface, and the rest is redistributed in the $2\{4 \text{ nearest planes}^7 \text{ . In these multilayers, the charge con nem ent to the rst plane increases for higher total$

charge densities in the lm^7 . Consequently, in the underdoped cuprate lm, despite larger $_{\rm TF}$, the low carrier density results in 80% of con ned charge (mechanism s to achieve stronger con nem ent have been studied in Ref. 8). In the overdoped lm, about 100% of the injected charge is con ned⁷. As in both cases the calculated

eld-accum ulated charge densities are roughly equal, one should expect sim ilar shifts of $T_{\rm c}$ both in the under- and overdoped $\,$ lm s. This sim ilarity in plies that without consideration of the microscopic processes at the gate/ $\,$ lm interface, the eld doping alone cannot satisfactorily explain the doping dependences of the $T_{\rm c}$ shift.

In a typical SuFET, the strong m odulation of injected carriers requires a gate polarization in the range 10{ 30 C/cm^2 . To achieve this polarization, one uses gates with dielectric constant in the range 20{100, fabricated from complex perovskite transition metal oxides like SrT iO₃ (STO). Here, extensive studies⁹ show that a fundam ental property is the hybridization of oxygen (0) p- and transition metal (Ti) d-orbitals caused by the Ti{O-displacements. The Coulomb interaction Vpd of a sm all am ount of injected holes with the hybridized p-d electrons in the insulating gate remains almost un-1{2 eV the spatial distance between the screened, V_{pd} nearest interface unit cells of gate and lm is about 2:5{ 5 A. M oreover, the holes strongly interact with optical T iO -phonons which polarize the interface. These excitation processes at the interface can possibly lead to charge localization. A further reason for interface charge trapping can be an increased disorder at the cuprate/STOinterface which can lead to Anderson localization. In fact, interface localization is experimentally supported by a hysteresis of the norm al state resistance and by the voltage dependence of the hole m obility in HTSC/STOheterostructures^{4,10}. There are also clear experimental indications that in organic eld e ect transistors, where a similar mechanism of the electric eld e ect applies, the carrier m obility decreases with increasing $\frac{11}{\cdot}$

As a step towards an understanding of the cooperative interface phenomena in correlated oxides, we present a theoretical study of eld-doped heterostructures, whereby we focus on two key aspects: (i) the interaction of the injected charge carriers with p-d-electrons in the dielectric gate, and (ii) the coupling of carriers to dynam ical lattice distortions. We nd that these processes at the gate/ lm interface result in dram atic m odi cations of the superconducting state with increasing eld-induced carrier density.

II. M ICROSCOPIC SCHEME OF THE ELECTRIC FIELD EFFECT

To analyze the eld dependence of the p-d hybridization at the gate interface, we introduce a model on a 2D – square lattice containing N₂ sites, where each site corresponds to a perovskite unit cell. In each O₆-octahedron of the i-th cell we consider a single T iD ionic group with a dynamical covalent bond along the eld direction perpendicular to the gate/ Im -interface (shown in Fig. 1). In this T iD group, we include only two states (p and d) expressed by the operators $d_i^y(d_i)$ and $p_i^y(p_i)$ which obey the one-electron constraint $d_i^yd_i + p_i^yp_i = 1$. In a SuFET, the gate electric eld "g a ects the p-d-electron transfer:

$$H_{pd} = \frac{1}{2} \int_{pd}^{0} (d_{i}^{y}d_{i} - p_{i}^{y}p_{i}) + E_{pd} \int_{i}^{X} (p_{i}^{y}d_{i} + d_{i}^{y}p_{i}):$$
(1)

The energy gap $^0_{pd}$ is about 3 eV in perovskite dielectric states, but decreases down to 1:5 eV in ferroelectric

In s due to modi cations of surface electronic states⁴. The electrostatic interaction $E_{pd} = "_q d_{pd}$ of the gate eld with the dipole m om ent, $d_{pd} = er_{pd}$, of the electron transfer increases the p-d level splitting and thus tends to localize the T iO -electron. Here e is the electron charge 2A is the T i-O distance. The energy gap $~^{\cup}_{\rm pd}$ and r_{pd} in (1) refers to $"_q = 0$. In a nonzero electric eld, which "g, the eld-dependent T iO induces a polarization P ... distortions u_i P_* in ply ${}^{0}_{pd} = {}^{0}_{pd} + {}^{*}u_i$. The eld e ect can be taken into account via the expansion of ${}^{"}_{pd}$ in powers of P_": $"_{pd} = "_{pd} (P_S^0 + \frac{\partial P_S^0}{\partial (m_g^0)} m_g)$, which deter- $\frac{e_{pd}^{0}}{e_{s}^{0}} \frac{e_{s}^{0}}{e_{s}^{0}}$. In this STO m ines the "susceptibility" " In s, the high concentration of oxygen vacancies leads to local polar regions and to a quasistatic polarization P_S⁰ \in 0¹² The additional, maximal electric eld-induced polarization is comparable to P_s^0 and the in uence of " on P_s is relatively weak compared to the e ect produced by the polar regions. Therefore, for the considered range of $"_g < 10^6 \text{ V/cm}$, we have $""_g P_S^0$ and consequently we take $"_{ps} = 0_{pd}^0$ in (1).

Furtherm ore, we assume that the barrier for a p-d-transfer (described by the second term in (1)) is modiled by the interface coupling to the carriers in the superconducting Im

$$H_{exc} = V_{pd} (1 n_{i}) (p_{i}^{y} d_{i} + d_{i}^{y} p_{i}):$$
 (2)

We consider in (2) the coupling with holes, where $n_{\rm i}$ is the electron number operator with spin $\,$, and $n_{\rm i}$ =

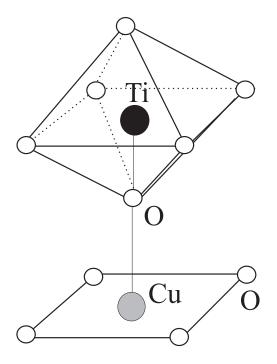


FIG.1: Schem atic presentation of a possible interface bonding in HTSC/STO heterostructure. The TiD group of TiD₆-octahedron which is directed perpendicular to the interface, is bonded to the Cu²⁺ ion of the interface CuO₂-plane of the cuprate superconducting lm.

Ρ

 n_i . The mechanism (2) can lead to a local effective attraction between the injected carriers, which has recently been analyzed for weak-coupling s-wave superconductors¹⁵.

The role of the TiO -distortions is more subtle. As shown in Ref. 16, the coupling of the injected charge to a static displacement only shifts the chemical potential in the lm. Consequently, we neglect the coupling to static distortions and we focus instead on dynamical TiO -displacements. We are interested in the coupling to the low -energy soft TO₁-mode, the polar component of which is hardened up to 50{80 cm⁻¹ at low T in STO thin lms in electric elds². Also, we consider higher-energy polar phonons like the TO₂- (170 cm⁻¹) or the TO₄-mode (545 cm⁻¹). At the gate/ lm-interface, such TiO -displacements are coupled to the holes in the lm

$$H_{pol} = ~!_{TO} ~ b_{i}^{y} b_{i} ~ 0 ~ (1 ~ n_{i}) (b_{i}^{y} + b_{i}); ~ (3)$$

where the phonon operators $b_i^y(b_i)$ refer to a particular T iO -m ode of energy $!_{TO}$, $_0 = \frac{p_{TO}E_p}{r!_{TO}E_p}$ is the holephonon coupling, and E_p is the polaron binding energy.

In the superconducting Im, we focus only on the rst plane (ideal con nem ent) without detailed analysis of the interplanar charge redistribution. We treat the Im in term s of a 2D Hubbard model which contains on-site correlations with a nearest and next-nearest tight-binding dispersion $\mathbf{W}_{k} = 2t(\cos k_{x} + \cos k_{y}) + 4t \cos k_{x} \cos k_{y}$:

$$H_{lm} = \frac{X}{k} C_{k}^{Y} C_{k} + U n_{i''} n_{i\#}; \qquad (4)$$

where c_k^y are electron creation operators. We choose the typical values $t^0 = t = 0.3$ and U = 8t. For the doped Cu 3d band, the electrive H am iltonian (4) describes the motion of hole singlets through the lattice of Cu²⁺ -ions in CuO₂-planes. These spin singlets are formed by the Cu hole and the O hole of the O-plaquette which is hybridized with the d-states of Cu²⁺ ions.¹³

The combined model (1) { (4) now presents a elddriven two-layer interface system in which the strongly correlated charge carriers in the Im are coupled to T iO excitons and to phonon states of the gate. Fig. 1 shows a possible bonding at a CuO_2/STO -interface. Here the oxygen ion is located between T i^{4+} and C u^{2+} form ing a TiO-Cu bond with the shortest distance between Cu (Im) and 0 (STO-gate) as compared to other possible chemical bonding con gurations which can appear in HTSC/STO-heterostructures. The coupling (2){(3) between the Cu holes and TiO-excitations results in a renorm alization of the CuO-hybridization amplitude $t_{C,u,0}$ in the planar C uO -squares and, consequently, in a renorm alization of the e ective hole hopping param eters $t = t_{C u0}^2 = {}_{p}^{u0}$ (" $_{p}^{o}$ is the energy of the planar 0 p-state) and t⁰. In addition, in the con guration shown in Fig. 1 we also obtain an attractive correction to the one-site repulsion U. To analyze the resulting electronic parameters in the lm, we rst derive an e ective Hubbard model by tracing over phonon and exciton degrees of freedom and subsequently we map this system onto a t{J-m odel with an e ective spin exchange energy $J_e = 4t_e^2 = U_e$.

III. COOPERATIVE p-d-EXCITON & POLARON EFFECT

We investigate rst the T iO hybridization (1) { (2). To eliminate rst order coupling terms in V_{pd}we apply the unitary transformation $U_{exc} = exp[_{pd} _{i} s_{i}^{y}n_{i}]$ to $H_{pd} + H_{exc} + H_{lm}$ with $s_i^y = i(d_{dp}^y p_i - p_i^y d_i)$, $p_d =$ $V_{pd} \stackrel{0}{}_{pd}=4(2_{pd}^{2}+2V_{pd}E_{pd}) \text{ and } p_{d}=\frac{1}{E_{pd}^{2}+(0_{pd}^{0}=2)^{2}}.$ Averaging the obtained expansion over p-d-exciton states, we nd a reduction of the electron hopping param eters t and t⁰ by the factor $_{pd} = \cos^2 _{pd}$. For the considered range of $V_{\rm pd}$, the attractive corrections ~ U $_{\rm pd}$ to U are small, $U_{pd}=U$ 02, and result in a maximal increase of J_e =J 1:07. Consequently, in distinction to weak-coupling superconductors¹⁵, this contribution of the p-d transfer to the increase of $T_{\rm c}$ is insigni cant. In contrast, a pronounced renorm alization of Je originates from the kinetic term $t_{\rm e}~$ = t $_{\rm pd}$. For $V_{\rm pd}{}=~^0_{\rm pd}$ 1, we nd that te =t can be reduced by pd down to 0:7.0n the other hand, the application of an electric eld enhances the exciton factor pd ! 1 and hence counteracts

polaron localization. This may cause a eld-tuned debcalization of holes in the lm when we take into account both, p-d-transfer and T iO -phonons.

The electron-phonon coupling in H _{pol} results in a polaron e ect at the gate/ lm -interface. W ith the soft phonon m ode, the typical values for the interface coupling 0 0:01{0:1 eV in ply large polaronic energies $E_p = ~!_{TO}$ 0:1{5, where the T iD m ode energy $~!_{TO} = t$ 10² {10¹ (t 0:25 eV) can be close to the adiabatic limit. To diagonalize (3), we apply a variational Lang-F irsov transform ation $U_{pol}(u_i; ;)^{17}$. The variational parameter describes the strength of the polaron e ect, u_i presents interface static distortions, and allows for anharm onic excitations. We assume ho-

mogeneity in the low-tem perature state of the doped Im and therefore replaced the site-glependent parameters by their averages: $u_i = u_i N_2^{-1} I_{i} ln_i i = 1 x$. In the electronic Ham iltonian H lm, the hopping energiest and t⁰ are reduced by the polaron band narrow ing factor pol() = exp[² E_p=~!_{TO} coth $\frac{1}{2} ~ !_{TO}$] where = exp(4). The parameters u, and are determ ined by m inim ization of HU_{pol}^{y} (H pol+ H lm) Upoli, which is averaged over the phonon vacuum^{17,18}. In particular, for we have the follow ing self-consistent equation:

= 1 1 (=~ I_{ro}) e_K (x) pd pol; (5)

where $e_{K}(x) = 2(t+\frac{6}{3})(1-x)$ is obtained from the average kinetic energy in H_{im}, which controls the dependence of on x. For low x, the contribution of e_{K} to the denominator in (5) is signi cant which results in small and weak polaron band narrowing pol(). On the other hand, when the hole-phonon coupling is strong and x increases, approaches 1, which leads to a localization of holes. This signi es that the reduced kinetic energy at su cient concentration of holes triggers the polaronic localization transition¹⁸. Consequently, the exchange energy J_e which is controlled by $t_e = t_{pd pol}$, is drastically suppressed (Fig. 2). For the soft T iD -m ode (Fig. 2 (a)), a suppression of J_e is obtained for $E_p=t > 1$

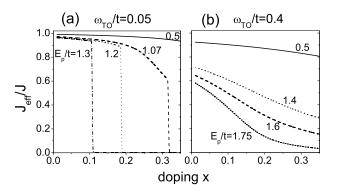


FIG.2: E ective exchange energy J_e vs hole doping x for $_{pd}=4t = 3.0$, $V_{pd}=4t = 0.5$, " $_g = 0$, and di erent polaron energies E_p (in units of t) in the case of coupling to (a) a soft m ode \sim ! TO =t = 0.05; (b) a high-energy m ode \sim ! TO =t = 0.4.

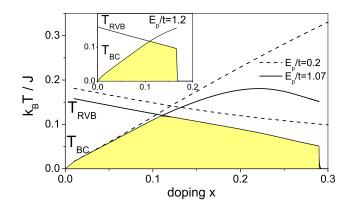


FIG.3: Phase diagram for d-wave superconductivity (shaded area) for three distinct polaron energies. Here J=t = 0.5, V_{pd} =4t= 1:0, ${}_{pd}^{0}$ =4t= 3:0, and ~!_{TO}=t= 0:05.

in the relevant range x < 0.3. Coupling instead to the high-energy mode (Fig. 2(b)) increases the minimal values of E_p required for the localization, and therefore the suppression of J_e is substantially weaker.

IV . $\operatorname{SUPERCONDUCTIVITY}$ IN THE FILM

For our considerations it is important that for all widely discussed concepts of high-T_c superconductivity, a suppression of J_e is feasible due to the loss of the kinetic energy by interface localization. This suppression may in fact result in lower pseudogap tempera- J_c and critical temperature T_c . In order ture T to relate our ndings to a distinct model, we approach the superconductivity in the strongly correlated electronic system within a slave-boson approach¹⁹. In this scheme spin-carrying ferm ions fi and spinless bosons h_i are introduced through $c_i = f_i^y h_i$ whereby the constraint $f_i^y f_i + h_i^y h_i = 1$ is to be enforced. We consider the pairing $ij = (3J_e = 4)$ $hf_i f_j$ f_i f_j i, hf^y_i f_i i and boson condensabond _{ij} = (3J_e =4) = $hh_i i^2$ order parameters. W ith the mean-eld tion factorization of the t{J H am iltonian, focusing on the uniform solutions $_{ij} = (1)^{i_y + j_y} d, i_j =$, we obtain a free energy, which is to be minimized with respect to d, , . The system of selfconsistent equations for the order param eters has been solved num erically. The pairing am plitude $_{\rm d}$ determ ines the tem perature $T_{\rm RV\,B}$, whereas the boson tem perature $T_{\mbox{\scriptsize BC}}$ has been estimated according to^{19,20} from the kinetic energy of the boson pairs assum ing a weak $t_{?} = t = 10^{4}$ interplanar coupling in the

In . The results are shown in the form of (T, x)-phase diagrams in Fig.3 for di erent values of the polaron energy $E_{\rm p}$, where $T_{\rm c}$ corresponds to the lowest temperature among $T_{\rm RVB}$ and $T_{\rm BC}$. In Fig.3, the gate eld is $"_g$ = 0, and the standard phase diagram same modiled essentially due to the interface coupling with the softm ode. Here, at low doping x < 0:12, the superconducting region is lim –

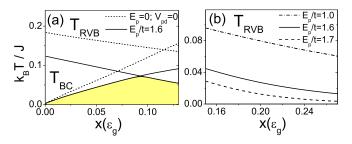


FIG.4: Field-dependent doping x ("_g) raised from initial values (a) $x_0 = 0$ and (b) $x_0 = 0.15$: phase diagrams for dwave superconductivity for di erent polaronic energies E_p; $V_{pd}=4t=1$, ${}^0_{pd}=4t=3$, and ~!_{T0}=t=0.4.

ited by T_{BC} , and for larger x by T_{RVB} . The increase of the polaron energy E $_{\rm p}$ $\,$ rst a $\,$ ects the overdoped region $\,$ where the right boundary of the superconducting phase is shifted from x_m 0:3 to 0:17 as E_p =t increases to 1:2. W ith a further increase of E_p , the collaps of T_{RVB} lim its the superconducting state also in the underdoped region: the maximally achievable doping, x_m , for superconductivity to prevail is $x_m = 0$:1 for $E_p = t = 1$:3, already below \optim aldoping". This is in striking contrast to the classical HTSC -behavior where T_c, after approaching its maximum at optim aldoping, sm oothly decreases to 0 as x ! 0:3. Finally, with $E_p = t > 1:4$, the superconducting region disappears due to the suppression of pairing by the soft-mode excitations in the gate. Note that for a Im containing more than one superconducting plane, the suppression of pairing is incomplete 21 .

For the eld tuned heterostructures, eld-dependent phase diagram s are required. F ig. 4 shows the evolution of such a phase diagram with the increase of the interface polaron energy E_p. The hole doping x ("g) m easures the density of holes injected by "g into the lm which is initially in the insulating $(x_0 = 0, Fig. 4(a))$ or in the superconducting $(x_0 = 0.15, Fig. 4(b))$ state. Here, $x("_{q}) = Q = N_{2}$ with the charge Q = CV, the dielectric capacitance C = 0 N₂ a²=d, the lattice constant a, the thickness of the dielectric lm d, and the bias voltage $V = "_{a}d$. For $x_{0} = 0$, the maximally achievable eld 10° V/cm for a gate with = 100 allows to attain a doping of x 0:13, which still is in the underdoped range (Fig. 4(a)). The decrease of J_e for larger E_p leads to the suppression of both $T_{\mbox{\scriptsize BC}}$ and $T_{\mbox{\scriptsize RVB}}$. These tem peratures also rem ain strongly dependent on "g. In contrast, for $x_0 = 0.15$, when doping x ("_q) is raised into the overdoped range, the increase of the polaron energy E $_{\rm p}$ not merely suppresses $T_{\rm RV\,B}\,$ (which lim its the superconducting region), but also reduces the slope of T_{RVB} with respect to $x("_q)$. The latter e ect results in a decrease of the T_c shift, $T_c = T_{RVB} (x_0 + x ("_q))$ $T_{RVB}(x_0)$, where the eld " in jects the hole density x = 0.03into the lm. The corresponding shifts are presented in Fig. 5 and show a strong decrease of T_c for $E_p = t > 12$ in the overdoped range, whereas in the underdoped Im s T_c decreases but remains nite. This result supports

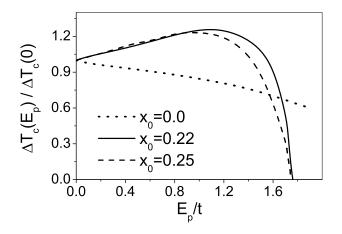


FIG.5:Field-induced shift T $_{\rm c}$ vsE $_{\rm p}$ scaled by T $_{\rm c}$ (E $_{\rm p}$ = 0). Here V_{pd}=4t= 1, $_{\rm pd}^{0}$ =4t= 3, and ~! $_{\rm TO}$ =t= 0:4.

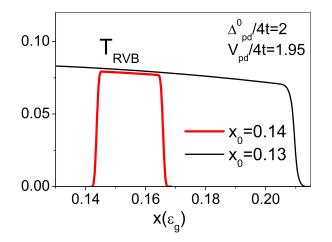


FIG. 6: Reentrant behavior of $T_{\rm RV\,B}$ for E $_{\rm p}{=}t$ = 1.0 and ${\sim}!_{\,{}_{\rm T\,O}}=t$ = 0.05.

the surprising fact that the eld does not substantially change T_c in the overdoped Im s.

The hole localization, which is also supported by experiments¹⁰, presents a serious challenge to current attempts to induce superconductivity in the strongly correlated Im s. However, a possible recipe how to delocalize the holes follows from the analysis of the coupling be-

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tween the CuO hole and p-d-TiO exciton. It was noted before that $"_{\rm g}$ increases the exciton factor $_{\rm pd}$ and enhances the hole motion for su ciently large exciton-hole interaction $V_{\rm pd}$. To analyze this e $\,\,{\rm ect}$, we investigate the region $x_0 = 0.13\{0.14 \text{ close to the transition into the}$ localized state where superconductivity is already suppressed, and then apply the eld. Due to the enhancement of t_e by $pd("_g)$, for $x_0 = 0$:14 we nd a reentrant transition (Fig. 6) into the superconducting state. W ith the injection of more holes by "g, the kinetic term in (5) is reduced which leads to a second suppression of $_{\rm pd}^{\rm U}$, the reensuperconductivity at x 0:17. For Vpd trant superconductivity is stable in a very narrow doping ⁰_{pd}, this range rapidly exrange (see Fig. 6). For $V_{pd} >$ tends over the full overdoped regime x 0:3. Such a strong V_{pd} , required for the hole delocalization, can be obtained in designed heterostructures with the holes in close proximity to the p-d T iO -orbitals where Cu-states share an apical oxygen with the adjacent Tias shown in Fig. 1. A ternatively, we propose to use multilayered cuprates with 3{5 CuO2-planes in a unit cell to delocalize the holes. Due to the small interplanar distance of 32A in some compounds, the polaron-suppressed hopping in the interface plane is in turn enhanced by the interplanar coupling to the subsequent planes.

We found that the cooperative e ect of interface hybridization and lattice dynamics in strongly correlated superconducting heterostructures is of crucial importance to their superconducting properties. The interface-caused suppression of T_c for higher doping is a possible explanation of the di erences in the electric elde ect in overdoped and underdoped SuFETs⁴. The highly non-trivial behavior of T_c under a variation of the eld allows to propose m echanism s for charge delocalization which is a subject of further experimental and theoretical studies.

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- 21 In an extended description of the $\,$ Im , m ore CuO $_2$ -planes should be coupled by interplanar electron tunneling. This e ectively leads to a reduction of phonon-induced localization of holes resulting in a suppressed but nite $T_{\rm c}$ for larger x.